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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	2880
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	113
Number of Gates	48000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx32a-1tq144i

Routing Resources

The routing and interconnect resources of SX-A devices are in the top two metal layers above the logic modules (Figure 1-1 on page 1-1), providing optimal use of silicon, thus enabling the entire floor of the device to be spanned with an uninterrupted grid of logic modules. Interconnection between these logic modules is achieved using the Actel patented metal-to-metal programmable antifuse interconnect elements. The antifuses are normally open circuits and, when programmed, form a permanent low-impedance connection.

Clusters and SuperClusters can be connected through the use of two innovative local routing resources called FastConnect and DirectConnect, which enable extremely fast and predictable interconnection of modules within Clusters and SuperClusters (Figure 1-5 on page 1-4 and Figure 1-6 on page 1-4). This routing architecture also dramatically reduces the number of antifuses required to complete a circuit, ensuring the highest possible performance, which is often required in applications such as fast counters, state machines, and data path logic. The interconnect elements (i.e., the antifuses and metal tracks) have lower capacitance and lower resistance than any other device of similar capacity, leading to the fastest signal propagation in the industry.

DirectConnect is a horizontal routing resource that provides connections from a C-cell to its neighboring R-Cell in a given SuperCluster. DirectConnect uses a hardwired signal path requiring no programmable

interconnection to achieve its fast signal propagation time of less than 0.1 ns.

FastConnect enables horizontal routing between any two logic modules within a given SuperCluster, and vertical routing with the SuperCluster immediately below it. Only one programmable connection is used in a FastConnect path, delivering a maximum pin-to-pin propagation time of 0.3 ns.

In addition to DirectConnect and FastConnect, the architecture makes use of two globally oriented routing resources known as segmented routing and high-drive routing. The Actel segmented routing structure provides a variety of track lengths for extremely fast routing between SuperClusters. The exact combination of track lengths and antifuses within each path is chosen by the 100% automatic place-and-route software to minimize signal propagation delays.

The general system of routing tracks allows any logic module in the array to be connected to any other logic or I/O module. Within this system, most connections typically require three or fewer antifuses, resulting in fast and predictable performance.

The unique local and general routing structure featured in SX-A devices allows 100% pin-locking with full logic utilization, enables concurrent printed circuit board (PCB) development, reduces design time, and allows designers to achieve performance goals with minimum effort.

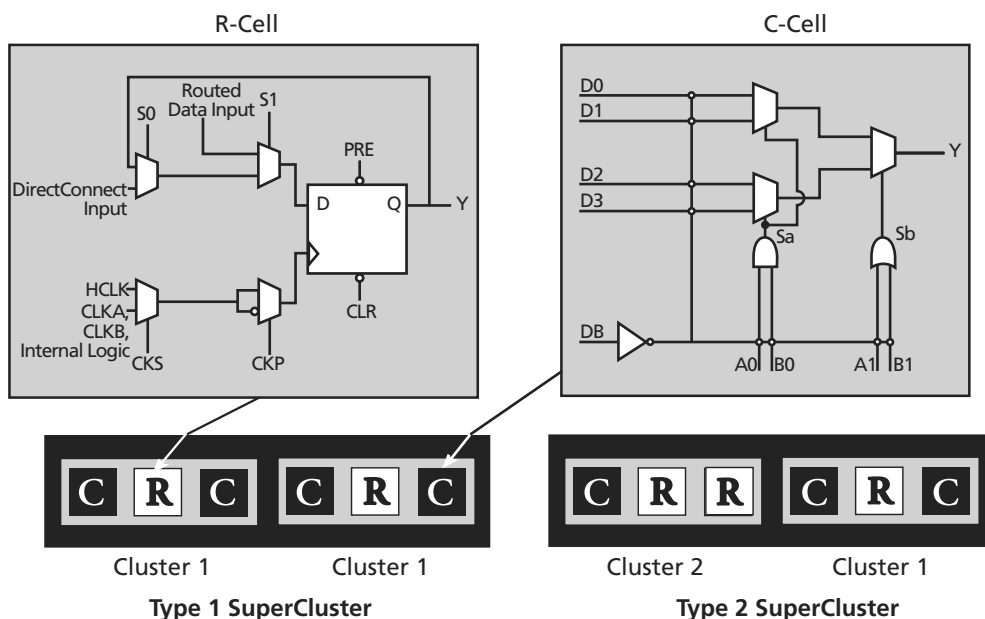


Figure 1-4 • Cluster Organization

JTAG Instructions

Table 1-7 lists the supported instructions with the corresponding IR codes for SX-A devices.

Table 1-8 lists the codes returned after executing the IDCODE instruction for SX-A devices. Note that bit 0 is always '1'. Bits 11-1 are always '02F', which is the Actel manufacturer code.

Table 1-7 • JTAG Instruction Code

Instructions (IR4:IR0)	Binary Code
EXTEST	00000
SAMPLE/PRELOAD	00001
INTEST	00010
USERCODE	00011
IDCODE	00100
HighZ	01110
CLAMP	01111
Diagnostic	10000
BYPASS	11111
Reserved	All others

Table 1-8 • JTAG Instruction Code

Device	Process	Revision	Bits 31-28	Bits 27-12
A54SX08A	0.22 μ	0	8, 9	40B4, 42B4
		1	A, B	40B4, 42B4
A54SX16A	0.22 μ	0	9	40B8, 42B8
		1	B	40B8, 42B8
	0.25 μ	1	B	22B8
A54SX32A	0.2 2 μ	0	9	40BD, 42BD
		1	B	40BD, 42BD
	0.25 μ	1	B	22BD
A54SX72A	0.22 μ	0	9	40B2, 42B2
		1	B	40B2, 42B2
	0.25 μ	1	B	22B2

Pin Description

CLKA/B, I/O **Clock A and B**

These pins are clock inputs for clock distribution networks. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. The clock input is buffered prior to clocking the R-cells. When not used, this pin must be tied Low or High (NOT left floating) on the board to avoid unwanted power consumption.

For A54SX72A, these pins can also be configured as user I/Os. When employed as user I/Os, these pins offer built-in programmable pull-up or pull-down resistors active during power-up only. When not used, these pins must be tied Low or High (NOT left floating).

QCLKA/B/C/D, I/O **Quadrant Clock A, B, C, and D**

These four pins are the quadrant clock inputs and are only used for A54SX72A with A, B, C, and D corresponding to bottom-left, bottom-right, top-left, and top-right quadrants, respectively. They are clock inputs for clock distribution networks. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. Each of these clock inputs can drive up to a quarter of the chip, or they can be grouped together to drive multiple quadrants. The clock input is buffered prior to clocking the R-cells. When not used, these pins must be tied Low or High on the board (NOT left floating).

These pins can also be configured as user I/Os. When employed as user I/Os, these pins offer built-in programmable pull-up or pull-down resistors active during power-up only.

GND **Ground**

Low supply voltage.

HCLK **Dedicated (Hardwired) Array Clock**

This pin is the clock input for sequential modules. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. This input is directly wired to each R-cell and offers clock speeds independent of the number of R-cells being driven. When not used, HCLK must be tied Low or High on the board (NOT left floating). When used, this pin should be held Low or High during power-up to avoid unwanted static power consumption.

I/O **Input/Output**

The I/O pin functions as an input, output, tristate, or bidirectional buffer. Based on certain configurations, input and output levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI or 5 V PCI specifications. Unused I/O pins are automatically tristated by the Designer software.

NC **No Connection**

This pin is not connected to circuitry within the device and can be driven to any voltage or be left floating with no effect on the operation of the device.

PRA/B, I/O **Probe A/B**

The Probe pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the other probe pin to allow real-time diagnostic output of any signal path within the device. The Probe pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality.

TCK, I/O **Test Clock**

Test clock input for diagnostic probe and device programming. In Flexible mode, TCK becomes active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDI, I/O **Test Data Input**

Serial input for boundary scan testing and diagnostic probe. In Flexible mode, TDI is active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDO, I/O **Test Data Output**

Serial output for boundary scan testing. In flexible mode, TDO is active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state. When Silicon Explorer II is being used, TDO will act as an output when the checksum command is run. It will return to user I/O when checksum is complete.

TMS **Test Mode Select**

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO, TRST). In flexible mode when the TMS pin is set Low, the TCK, TDI, and TDO pins are boundary scan pins (refer to Table 1-6 on page 1-9). Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the logic reset state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The logic reset state is reached five TCK cycles after the TMS pin is set High. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications.

TRST, I/O **Boundary Scan Reset Pin**

Once it is configured as the JTAG Reset pin, the TRST pin functions as an active low input to asynchronously initialize or reset the boundary scan circuit. The TRST pin is equipped with an internal pull-up resistor. This pin functions as an I/O when the **Reserve JTAG Reset Pin** is not selected in Designer.

V_{CC} **Supply Voltage**

Supply voltage for I/Os. See Table 2-2 on page 2-1. All V_{CC} power pins in the device should be connected.

V_{CCA} **Supply Voltage**

Supply voltage for array. See Table 2-2 on page 2-1. All V_{CCA} power pins in the device should be connected.

Detailed Specifications

Operating Conditions

Table 2-1 • Absolute Maximum Ratings

Symbol	Parameter	Limits	Units
V_{CCI}	DC Supply Voltage for I/Os	−0.3 to +6.0	V
V_{CCA}	DC Supply Voltage for Arrays	−0.3 to +3.0	V
V_I	Input Voltage	−0.5 to +5.75	V
V_O	Output Voltage	−0.5 to $+V_{CCI} + 0.5$	V
T_{STG}	Storage Temperature	−65 to +150	°C

Note: *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the "Recommended Operating Conditions".

Table 2-2 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Units
Temperature Range	0 to +70	−40 to +85	°C
2.5 V Power Supply Range (V_{CCA} and V_{CCI})	2.25 to 2.75	2.25 to 2.75	V
3.3 V Power Supply Range (V_{CCI})	3.0 to 3.6	3.0 to 3.6	V
5 V Power Supply Range (V_{CCI})	4.75 to 5.25	4.75 to 5.25	V

Typical SX-A Standby Current

Table 2-3 • Typical Standby Current for SX-A at 25°C with $V_{CCA} = 2.5$ V

Product	$V_{CCI} = 2.5$ V	$V_{CCI} = 3.3$ V	$V_{CCI} = 5$ V
A54SX08A	0.8 mA	1.0 mA	2.9 mA
A54SX16A	0.8 mA	1.0 mA	2.9 mA
A54SX32A	0.9 mA	1.0 mA	3.0 mA
A54SX72A	3.6 mA	3.8 mA	4.5 mA

Table 2-4 • Supply Voltages

V_{CCA}	V_{CCI}^*	Maximum Input Tolerance	Maximum Output Drive
2.5 V	2.5 V	5.75 V	2.7 V
2.5 V	3.3 V	5.75 V	3.6 V
2.5 V	5 V	5.75 V	5.25 V

Note: *3.3 V PCI is not 5 V tolerant due to the clamp diode, but instead is 3.3 V tolerant.

Electrical Specifications

Table 2-5 • 3.3 V LVTTTL and 5 V TTL Electrical Specifications

Symbol	Parameter		Commercial		Industrial		Units
			Min.	Max.	Min.	Max.	
V _{OH}	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OH} = −1 mA)	0.9 V _{CCI}		0.9 V _{CCI}		V
	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OH} = −8 mA)	2.4		2.4		V
V _{OL}	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OL} = 1 mA)	0.4		0.4		V
	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OL} = 12 mA)	0.4		0.4		V
V _{IL}	Input Low Voltage		0.8		0.8		V
V _{IH}	Input High Voltage		2.0	5.75	2.0	5.75	V
I _{IL} /I _{IH}	Input Leakage Current, V _{IN} = V _{CCI} or GND		−10	10	−10	10	μA
I _{OZ}	Tristate Output Leakage Current		−10	10	−10	10	μA
t _R , t _F	Input Transition Time t _R , t _F		10		10		ns
C _{IO}	I/O Capacitance		10		10		pF
I _{CC}	Standby Current		10		20		mA
IV Curve*	Can be derived from the IBIS model on the web.						

Note: *The IBIS model can be found at <http://www.actel.com/download/libis/default.aspx>.

Table 2-6 • 2.5 V LVC MOS2 Electrical Specifications

Symbol	Parameter		Commercial		Industrial		Units
			Min.	Max.	Min.	Max.	
V _{OH}	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OH} = -100 μA)	2.1		2.1		V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OH} = -1 mA)	2.0		2.0		V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OH} = -2 mA)	1.7		1.7		V
V _{OL}	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OL} = 100 μA)	0.2		0.2		V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OL} = 1 mA)	0.4		0.4		V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OL} = 2 mA)	0.7		0.7		V
V _{IL}	Input Low Voltage, V _{OUT} ≤ V _{VOL(max)}		-0.3	0.7	-0.3	0.7	V
V _{IH}	Input High Voltage, V _{OUT} ≥ V _{VOH(min)}		1.7	5.75	1.7	5.75	V
I _{IL} /I _{IH}	Input Leakage Current, V _{IN} = V _{CCI} or GND		-10	10	-10	10	μA
I _{OZ}	Tristate Output Leakage Current, V _{OUT} = V _{CCI} or GND		-10	10	-10	10	μA
t _R , t _F	Input Transition Time t _R , t _F		10		10		ns
C _{IO}	I/O Capacitance		10		10		pF
I _{CC}	Standby Current		10		20		mA
IV Curve*	Can be derived from the IBIS model on the web.						

Note: *The IBIS model can be found at <http://www.actel.com/download/libis/default.aspx>.

PCI Compliance for the SX-A Family

The SX-A family supports 3.3 V and 5 V PCI and is compliant with the PCI Local Bus Specification Rev. 2.1.

Table 2-7 • DC Specifications (5 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
V _{CCA}	Supply Voltage for Array		2.25	2.75	V
V _{CCI}	Supply Voltage for I/Os		4.75	5.25	V
V _{IH}	Input High Voltage		2.0	5.75	V
V _{IL}	Input Low Voltage		–0.5	0.8	V
I _{IH}	Input High Leakage Current ¹	V _{IN} = 2.7	–	70	μA
I _{IL}	Input Low Leakage Current ¹	V _{IN} = 0.5	–	–70	μA
V _{OH}	Output High Voltage	I _{OUT} = –2 mA	2.4	–	V
V _{OL}	Output Low Voltage ²	I _{OUT} = 3 mA, 6 mA	–	0.55	V
C _{IN}	Input Pin Capacitance ³		–	10	pF
C _{CLK}	CLK Pin Capacitance		5	12	pF

Notes:

1. Input leakage currents include hi-Z output leakage for all bidirectional buffers with tristate outputs.
2. Signals without pull-up resistors must have 3 mA low output current. Signals requiring pull-up must have 6 mA; the latter includes FRAME#, IRDY#, TRDY#, DEVSEL#, STOP#, SERR#, PERR#, LOCK#, and, when used AD[63::32], C/BE[7::4]#, PAR64, REQ64#, and ACK64#.
3. Absolute maximum pin capacitance for a PCI input is 10 pF (except for CLK).

Figure 2-1 shows the 5 V PCI V/I curve and the minimum and maximum PCI drive characteristics of the SX-A family.

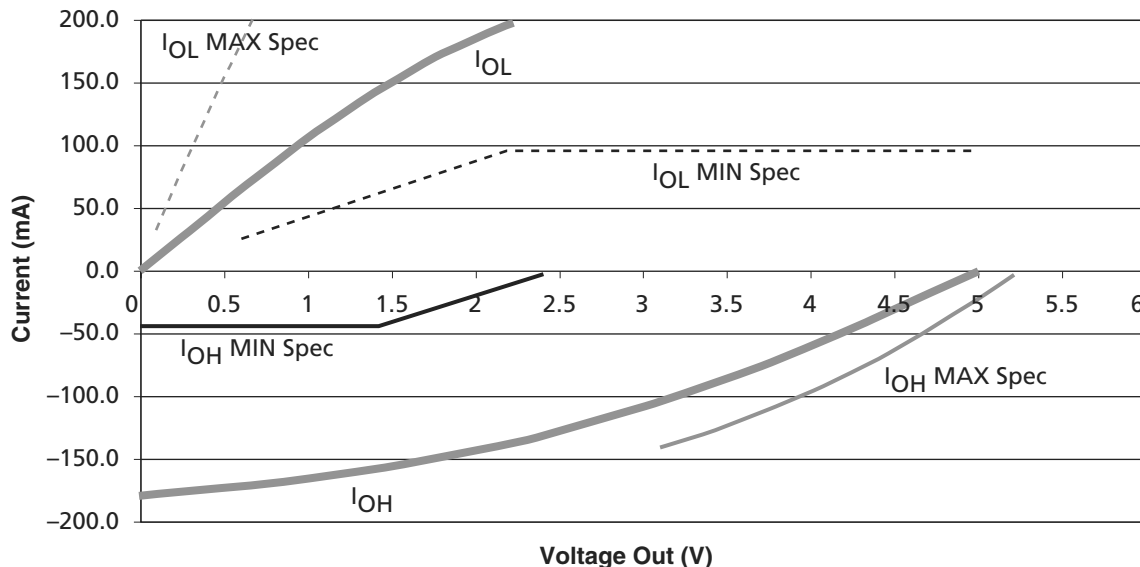


Figure 2-1 • 5 V PCI V/I Curve for SX-A Family

$$I_{OH} = 11.9 * (V_{OUT} - 5.25) * (V_{OUT} + 2.45)$$

for $V_{CCI} > V_{OUT} > 3.1V$

EQ 2-1

$$I_{OL} = 78.5 * V_{OUT} * (4.4 - V_{OUT})$$

for $0V < V_{OUT} < 0.71V$

EQ 2-2

Table 2-9 • DC Specifications (3.3 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
V_{CCA}	Supply Voltage for Array		2.25	2.75	V
V_{CCI}	Supply Voltage for I/Os		3.0	3.6	V
V_{IH}	Input High Voltage		$0.5V_{CCI}$	$V_{CCI} + 0.5$	V
V_{IL}	Input Low Voltage		-0.5	$0.3V_{CCI}$	V
I_{IPU}	Input Pull-up Voltage ¹		$0.7V_{CCI}$	–	V
I_{IL}	Input Leakage Current ²	$0 < V_{IN} < V_{CCI}$	-10	+10	μA
V_{OH}	Output High Voltage	$I_{OUT} = -500 \mu A$	$0.9V_{CCI}$	–	V
V_{OL}	Output Low Voltage	$I_{OUT} = 1,500 \mu A$		$0.1V_{CCI}$	V
C_{IN}	Input Pin Capacitance ³		–	10	pF
C_{CLK}	CLK Pin Capacitance		5	12	pF

Notes:

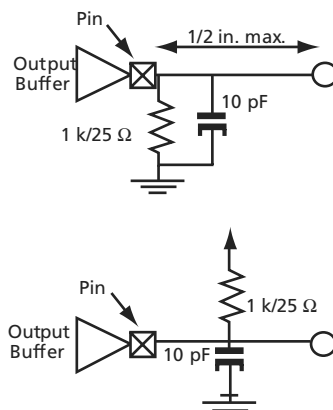
1. This specification should be guaranteed by design. It is the minimum voltage to which pull-up resistors are calculated to pull a floated network. Designers should ensure that the input buffer is conducting minimum current at this input voltage in applications sensitive to static power utilization.
2. Input leakage currents include hi-Z output leakage for all bidirectional buffers with tristate outputs.
3. Absolute maximum pin capacitance for a PCI input is 10 pF (except for CLK).

Table 2-10 • AC Specifications (3.3 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 0.3V_{CCI}^1$	$-12V_{CCI}$	–	mA
		$0.3V_{CCI} \leq V_{OUT} < 0.9V_{CCI}^1$	$(-17.1(V_{CCI} - V_{OUT}))$	–	mA
		$0.7V_{CCI} < V_{OUT} < V_{CCI}^{1,2}$	–	EQ 2-3 on page 2-7	–
	(Test Point)	$V_{OUT} = 0.7V_{CC}^2$	–	$-32V_{CCI}$	mA
$I_{OL(AC)}$	Switching Current Low	$V_{CCI} > V_{OUT} \geq 0.6V_{CCI}^1$	$16V_{CCI}$	–	mA
		$0.6V_{CCI} > V_{OUT} > 0.1V_{CCI}^1$	$(26.7V_{OUT})$	–	mA
		$0.18V_{CCI} > V_{OUT} > 0^{1,2}$	–	EQ 2-4 on page 2-7	–
	(Test Point)	$V_{OUT} = 0.18V_{CC}^2$	–	$38V_{CCI}$	mA
I_{CL}	Low Clamp Current	$-3 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$	–	mA
I_{CH}	High Clamp Current	$V_{CCI} + 4 > V_{IN} \geq V_{CCI} + 1$	$25 + (V_{IN} - V_{CCI} - 1)/0.015$	–	mA
$slew_R$	Output Rise Slew Rate	$0.2V_{CCI} - 0.6V_{CCI}$ load ³	1	4	V/ns
$slew_F$	Output Fall Slew Rate	$0.6V_{CCI} - 0.2V_{CCI}$ load ³	1	4	V/ns

Notes:

1. Refer to the *VII* curves in Figure 2-2 on page 2-7. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.
2. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (C and D) are provided with the respective diagrams in Figure 2-2 on page 2-7. The equation defined maximum should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.
3. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per the latest revision of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is required (the maximum is no longer simply a guideline). Rise slew rate does not apply to open drain outputs.



Guidelines for Estimating Power

The following guidelines are meant to represent worst-case scenarios; they can be generally used to predict the upper limits of power dissipation:

Logic Modules (m) = 20% of modules

Inputs Switching (n) = Number inputs/4

Outputs Switching (p) = Number of outputs/4

CLKA Loads (q1) = 20% of R-cells

CLKB Loads (q2) = 20% of R-cells

Load Capacitance (CL) = 35 pF

Average Logic Module Switching Rate (fm) = f/10

Average Input Switching Rate (fn) = f/5

Average Output Switching Rate (fp) = f/10

Average CLKA Rate (fq1) = f/2

Average CLKB Rate (fq2) = f/2

Average HCLK Rate (fs1) = f

HCLK loads (s1) = 20% of R-cells

To assist customers in estimating the power dissipations of their designs, Actel has published the *eX*, *SX-A* and *RT54SX-S* *Power Calculator* worksheet.

Thermal Characteristics

Introduction

The temperature variable in Actel Designer software refers to the junction temperature, not the ambient, case, or board temperatures. This is an important distinction because dynamic and static power consumption will cause the chip's junction to be higher than the ambient, case, or board temperatures. EQ 2-9 and EQ 2-10 give the relationship between thermal resistance, temperature gradient and power.

$$\theta_{JA} = \frac{T_J - T_A}{P}$$

EQ 2-9

$$\theta_{JA} = \frac{T_C - T_A}{P}$$

EQ 2-10

Where:

- θ_{JA} = Junction-to-air thermal resistance
- θ_{JC} = Junction-to-case thermal resistance
- T_J = Junction temperature
- T_A = Ambient temperature
- T_C = Ambient temperature
- P = total power dissipated by the device

Table 2-12 • Package Thermal Characteristics

Package Type	Pin Count	θ_{JC}	θ_{JA}			Units
			Still Air	1.0 m/s 200 ft./min.	2.5 m/s 500 ft./min.	
Thin Quad Flat Pack (TQFP)	100	14	33.5	27.4	25	°C/W
Thin Quad Flat Pack (TQFP)	144	11	33.5	28	25.7	°C/W
Thin Quad Flat Pack (TQFP)	176	11	24.7	19.9	18	°C/W
Plastic Quad Flat Pack (PQFP) ¹	208	8	26.1	22.5	20.8	°C/W
Plastic Quad Flat Pack (PQFP) with Heat Spreader ²	208	3.8	16.2	13.3	11.9	°C/W
Plastic Ball Grid Array (PBGA)	329	3	17.1	13.8	12.8	°C/W
Fine Pitch Ball Grid Array (FBGA)	144	3.8	26.9	22.9	21.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	256	3.8	26.6	22.8	21.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	484	3.2	18	14.7	13.6	°C/W

Notes:

- The A54SX08A PQ208 has no heat spreader.
- The SX-A PQ208 package has a heat spreader for A54SX16A, A54SX32A, and A54SX72A.

Timing Characteristics

Timing characteristics for SX-A devices fall into three categories: family-dependent, device-dependent, and design-dependent. The input and output buffer characteristics are common to all SX-A family members. Internal routing delays are device-dependent. Design dependency means actual delays are not determined until after placement and routing of the user's design are complete. The timing characteristics listed in this datasheet represent sample timing numbers of the SX-A devices. Design-specific delay values may be determined by using Timer or performing simulation after successful place-and-route with the Designer software.

Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most timing-critical paths. Critical nets are determined by net property assignment prior to placement and routing. Up to 6 percent of the nets in a design may be designated as critical, while 90 percent of the nets in a design are typical.

Long Tracks

Some nets in the design use long tracks. Long tracks are special routing resources that span multiple rows, columns, or modules. Long tracks employ three to five antifuse connections. This increases capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically, up to 6 percent of nets in a fully utilized device require long tracks. Long tracks contribute approximately 4 ns to 8.4 ns delay. This additional delay is represented statistically in higher fanout routing delays.

Timing Derating

SX-A devices are manufactured with a CMOS process. Therefore, device performance varies according to temperature, voltage, and process changes. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

Temperature and Voltage Derating Factors

Table 2-13 • Temperature and Voltage Derating Factors
(Normalized to Worst-Case Commercial, $T_J = 70^\circ\text{C}$, $V_{CCA} = 2.25\text{ V}$)

V_{CCA}	Junction Temperature (T_J)						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
2.250 V	0.79	0.80	0.87	0.89	1.00	1.04	1.14
2.500 V	0.74	0.75	0.82	0.83	0.94	0.97	1.07
2.750 V	0.68	0.69	0.75	0.77	0.87	0.90	0.99

Table 2-21 • A54SX16A Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed ¹		-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{INYH}	Input Data Pad to Y High 5 V PCI		0.5		0.5		0.6		0.7		0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI		0.7		0.8		0.9		1.1		1.5	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL		0.5		0.5		0.6		0.7		0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL		0.7		0.8		0.9		1.1		1.5	ns
Input Module Predicted Routing Delays²												
t_{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.3		0.4		0.6	ns
t_{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t_{IRD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t_{IRD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1.0		1.4	ns
t_{IRD8}	FO = 8 Routing Delay		1.2		1.4		1.5		0.8		2.5	ns
t_{IRD12}	FO = 12 Routing Delay		1.7		2.0		2.2		2.6		3.6	ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-35 • A54SX72A Timing Characteristics
(Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed ¹		-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays ²												
t _{PD}	Internal Array Module	1.0		1.1		1.3		1.5		2.0		ns
Predicted Routing Delays ³												
t _{DC}	FO = 1 Routing Delay, Direct Connect	0.1		0.1		0.1		0.1		0.1		ns
t _{FC}	FO = 1 Routing Delay, Fast Connect	0.3		0.3		0.3		0.4		0.6		ns
t _{RD1}	FO = 1 Routing Delay	0.3		0.3		0.4		0.5		0.7		ns
t _{RD2}	FO = 2 Routing Delay	0.4		0.5		0.6		0.7		1		ns
t _{RD3}	FO = 3 Routing Delay	0.5		0.7		0.8		0.9		1.3		ns
t _{RD4}	FO = 4 Routing Delay	0.7		0.9		1		1.1		1.5		ns
t _{RD8}	FO = 8 Routing Delay	1.2		1.5		1.7		2.1		2.9		ns
t _{RD12}	FO = 12 Routing Delay	1.7		2.2		2.5		3		4.2		ns
R-Cell Timing												
t _{RCO}	Sequential Clock-to-Q	0.7		0.8		0.9		1.1		1.5		ns
t _{CLR}	Asynchronous Clear-to-Q	0.6		0.7		0.7		0.9		1.2		ns
t _{PRESET}	Asynchronous Preset-to-Q	0.7		0.8		0.8		1.0		1.4		ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.3		1.5		1.7		2.0		2.8		ns
t _{RECASYN}	Asynchronous Recovery Time	0.3		0.4		0.4		0.5		0.7		ns
t _{HASYN}	Asynchronous Hold Time	0.3		0.3		0.3		0.4		0.6		ns
t _{MPW}	Clock Minimum Pulse Width	1.5		1.7		2.0		2.3		3.2		ns
Input Module Propagation Delays												
t _{INYH}	Input Data Pad to Y High 2.5 V LVCMOS	0.6		0.7		0.8		0.9		1.3		ns
t _{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS	0.8		1.0		1.1		1.3		1.7		ns
t _{INYH}	Input Data Pad to Y High 3.3 V PCI	0.6		0.7		0.7		0.9		1.2		ns
t _{INYL}	Input Data Pad to Y Low 3.3 V PCI	0.7		0.8		0.9		1.0		1.4		ns
t _{INYH}	Input Data Pad to Y High 3.3 V LVTTTL	0.7		0.7		0.8		1.0		1.4		ns
t _{INYL}	Input Data Pad to Y Low 3.3 V LVTTTL	1.0		1.2		1.3		1.5		2.1		ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-36 • A54SX72A Timing Characteristics (Continued)
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{QCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		3.0		3.4		3.9		4.6		6.4	ns
t_{QCHKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.9		3.4		3.8		4.5		6.3	ns
t_{QPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t_{QPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t_{QCKSW}	Maximum Skew (Light Load)		0.2		0.3		0.3		0.3		0.5	ns
t_{QCKSW}	Maximum Skew (50% Load)		0.4		0.5		0.5		0.6		0.9	ns
t_{QCKSW}	Maximum Skew (100% Load)		0.4		0.5		0.5		0.6		0.9	ns

Note: *All –3 speed grades have been discontinued.

100-TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	TMS	TMS	TMS
8	V _{CCI}	V _{CCI}	V _{CCI}
9	GND	GND	GND
10	I/O	I/O	I/O
11	I/O	I/O	I/O
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	TRST, I/O	TRST, I/O	TRST, I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	V _{CCI}	V _{CCI}	V _{CCI}
21	I/O	I/O	I/O
22	I/O	I/O	I/O
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	I/O	I/O	I/O
29	I/O	I/O	I/O
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	PRB, I/O	PRB, I/O	PRB, I/O
35	V _{CCA}	V _{CCA}	V _{CCA}

100-TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
36	GND	GND	GND
37	NC	NC	NC
38	I/O	I/O	I/O
39	HCLK	HCLK	HCLK
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	V _{CCI}	V _{CCI}	V _{CCI}
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	TDO, I/O	TDO, I/O	TDO, I/O
50	I/O	I/O	I/O
51	GND	GND	GND
52	I/O	I/O	I/O
53	I/O	I/O	I/O
54	I/O	I/O	I/O
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	V _{CCA}	V _{CCA}	V _{CCA}
58	V _{CCI}	V _{CCI}	V _{CCI}
59	I/O	I/O	I/O
60	I/O	I/O	I/O
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	V _{CCA}	V _{CCA}	V _{CCA}
68	GND	GND	GND
69	GND	GND	GND
70	I/O	I/O	I/O

256-Pin FBGA			
Pin Number	A545X16A Function	A545X32A Function	A545X72A Function
E11	I/O	I/O	I/O
E12	I/O	I/O	I/O
E13	NC	I/O	I/O
E14	I/O	I/O	I/O
E15	I/O	I/O	I/O
E16	I/O	I/O	I/O
F1	I/O	I/O	I/O
F2	I/O	I/O	I/O
F3	I/O	I/O	I/O
F4	TMS	TMS	TMS
F5	I/O	I/O	I/O
F6	I/O	I/O	I/O
F7	V _{CCI}	V _{CCI}	V _{CCI}
F8	V _{CCI}	V _{CCI}	V _{CCI}
F9	V _{CCI}	V _{CCI}	V _{CCI}
F10	V _{CCI}	V _{CCI}	V _{CCI}
F11	I/O	I/O	I/O
F12	V _{CCA}	V _{CCA}	V _{CCA}
F13	I/O	I/O	I/O
F14	I/O	I/O	I/O
F15	I/O	I/O	I/O
F16	I/O	I/O	I/O
G1	NC	I/O	I/O
G2	I/O	I/O	I/O
G3	NC	I/O	I/O
G4	I/O	I/O	I/O
G5	I/O	I/O	I/O
G6	V _{CCI}	V _{CCI}	V _{CCI}
G7	GND	GND	GND
G8	GND	GND	GND
G9	GND	GND	GND
G10	GND	GND	GND
G11	V _{CCI}	V _{CCI}	V _{CCI}
G12	I/O	I/O	I/O
G13	GND	GND	GND
G14	NC	I/O	I/O
G15	V _{CCA}	V _{CCA}	V _{CCA}

256-Pin FBGA			
Pin Number	A545X16A Function	A545X32A Function	A545X72A Function
G16	I/O	I/O	I/O
H1	I/O	I/O	I/O
H2	I/O	I/O	I/O
H3	V _{CCA}	V _{CCA}	V _{CCA}
H4	TRST, I/O	TRST, I/O	TRST, I/O
H5	I/O	I/O	I/O
H6	V _{CCI}	V _{CCI}	V _{CCI}
H7	GND	GND	GND
H8	GND	GND	GND
H9	GND	GND	GND
H10	GND	GND	GND
H11	V _{CCI}	V _{CCI}	V _{CCI}
H12	I/O	I/O	I/O
H13	I/O	I/O	I/O
H14	I/O	I/O	I/O
H15	I/O	I/O	I/O
H16	NC	I/O	I/O
J1	NC	I/O	I/O
J2	NC	I/O	I/O
J3	NC	I/O	I/O
J4	I/O	I/O	I/O
J5	I/O	I/O	I/O
J6	V _{CCI}	V _{CCI}	V _{CCI}
J7	GND	GND	GND
J8	GND	GND	GND
J9	GND	GND	GND
J10	GND	GND	GND
J11	V _{CCI}	V _{CCI}	V _{CCI}
J12	I/O	I/O	I/O
J13	I/O	I/O	I/O
J14	I/O	I/O	I/O
J15	I/O	I/O	I/O
J16	I/O	I/O	I/O
K1	I/O	I/O	I/O
K2	I/O	I/O	I/O
K3	NC	I/O	I/O
K4	V _{CCA}	V _{CCA}	V _{CCA}

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
K5	I/O	I/O	I/O
K6	V _{CCI}	V _{CCI}	V _{CCI}
K7	GND	GND	GND
K8	GND	GND	GND
K9	GND	GND	GND
K10	GND	GND	GND
K11	V _{CCI}	V _{CCI}	V _{CCI}
K12	I/O	I/O	I/O
K13	I/O	I/O	I/O
K14	I/O	I/O	I/O
K15	NC	I/O	I/O
K16	I/O	I/O	I/O
L1	I/O	I/O	I/O
L2	I/O	I/O	I/O
L3	I/O	I/O	I/O
L4	I/O	I/O	I/O
L5	I/O	I/O	I/O
L6	I/O	I/O	I/O
L7	V _{CCI}	V _{CCI}	V _{CCI}
L8	V _{CCI}	V _{CCI}	V _{CCI}
L9	V _{CCI}	V _{CCI}	V _{CCI}
L10	V _{CCI}	V _{CCI}	V _{CCI}
L11	I/O	I/O	I/O
L12	I/O	I/O	I/O
L13	I/O	I/O	I/O
L14	I/O	I/O	I/O
L15	I/O	I/O	I/O
L16	NC	I/O	I/O
M1	I/O	I/O	I/O
M2	I/O	I/O	I/O
M3	I/O	I/O	I/O
M4	I/O	I/O	I/O
M5	I/O	I/O	I/O
M6	I/O	I/O	I/O
M7	I/O	I/O	QCLKA
M8	PRB, I/O	PRB, I/O	PRB, I/O
M9	I/O	I/O	I/O

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
M10	I/O	I/O	I/O
M11	I/O	I/O	I/O
M12	NC	I/O	I/O
M13	I/O	I/O	I/O
M14	NC	I/O	I/O
M15	I/O	I/O	I/O
M16	I/O	I/O	I/O
N1	I/O	I/O	I/O
N2	I/O	I/O	I/O
N3	I/O	I/O	I/O
N4	I/O	I/O	I/O
N5	I/O	I/O	I/O
N6	I/O	I/O	I/O
N7	I/O	I/O	I/O
N8	I/O	I/O	I/O
N9	I/O	I/O	I/O
N10	I/O	I/O	I/O
N11	I/O	I/O	I/O
N12	I/O	I/O	I/O
N13	I/O	I/O	I/O
N14	I/O	I/O	I/O
N15	I/O	I/O	I/O
N16	I/O	I/O	I/O
P1	I/O	I/O	I/O
P2	GND	GND	GND
P3	I/O	I/O	I/O
P4	I/O	I/O	I/O
P5	NC	I/O	I/O
P6	I/O	I/O	I/O
P7	I/O	I/O	I/O
P8	I/O	I/O	I/O
P9	I/O	I/O	I/O
P10	NC	I/O	I/O
P11	I/O	I/O	I/O
P12	I/O	I/O	I/O
P13	V _{CCA}	V _{CCA}	V _{CCA}
P14	I/O	I/O	I/O

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
P15	I/O	I/O	I/O
P16	I/O	I/O	I/O
R1	I/O	I/O	I/O
R2	GND	GND	GND
R3	I/O	I/O	I/O
R4	NC	I/O	I/O
R5	I/O	I/O	I/O
R6	I/O	I/O	I/O
R7	I/O	I/O	I/O
R8	I/O	I/O	I/O
R9	HCLK	HCLK	HCLK
R10	I/O	I/O	QCLKB
R11	I/O	I/O	I/O
R12	I/O	I/O	I/O
R13	I/O	I/O	I/O
R14	I/O	I/O	I/O
R15	GND	GND	GND
R16	GND	GND	GND
T1	GND	GND	GND
T2	I/O	I/O	I/O
T3	I/O	I/O	I/O
T4	NC	I/O	I/O
T5	I/O	I/O	I/O
T6	I/O	I/O	I/O
T7	I/O	I/O	I/O
T8	I/O	I/O	I/O
T9	V _{CCA}	V _{CCA}	V _{CCA}
T10	I/O	I/O	I/O
T11	I/O	I/O	I/O
T12	NC	I/O	I/O
T13	I/O	I/O	I/O
T14	I/O	I/O	I/O
T15	TDO, I/O	TDO, I/O	TDO, I/O
T16	GND	GND	GND

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
A1	NC*	NC
A2	NC*	NC
A3	NC*	I/O
A4	NC*	I/O
A5	NC*	I/O
A6	I/O	I/O
A7	I/O	I/O
A8	I/O	I/O
A9	I/O	I/O
A10	I/O	I/O
A11	NC*	I/O
A12	NC*	I/O
A13	I/O	I/O
A14	NC*	NC
A15	NC*	I/O
A16	NC*	I/O
A17	I/O	I/O
A18	I/O	I/O
A19	I/O	I/O
A20	I/O	I/O
A21	NC*	I/O
A22	NC*	I/O
A23	NC*	I/O
A24	NC*	I/O
A25	NC*	NC
A26	NC*	NC
AA1	NC*	I/O
AA2	NC*	I/O
AA3	V _{CCA}	V _{CCA}
AA4	I/O	I/O
AA5	I/O	I/O
AA22	I/O	I/O
AA23	I/O	I/O
AA24	I/O	I/O
AA25	NC*	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
AA26	NC*	I/O
AB1	NC*	NC
AB2	V _{CCI}	V _{CCI}
AB3	I/O	I/O
AB4	I/O	I/O
AB5	NC*	I/O
AB6	I/O	I/O
AB7	I/O	I/O
AB8	I/O	I/O
AB9	I/O	I/O
AB10	I/O	I/O
AB11	I/O	I/O
AB12	PRB, I/O	PRB, I/O
AB13	V _{CCA}	V _{CCA}
AB14	I/O	I/O
AB15	I/O	I/O
AB16	I/O	I/O
AB17	I/O	I/O
AB18	I/O	I/O
AB19	I/O	I/O
AB20	TDO, I/O	TDO, I/O
AB21	GND	GND
AB22	NC*	I/O
AB23	I/O	I/O
AB24	I/O	I/O
AB25	NC*	I/O
AB26	NC*	I/O
AC1	I/O	I/O
AC2	I/O	I/O
AC3	I/O	I/O
AC4	NC*	I/O
AC5	V _{CCI}	V _{CCI}
AC6	I/O	I/O
AC7	V _{CCI}	V _{CCI}
AC8	I/O	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
AC9	I/O	I/O
AC10	I/O	I/O
AC11	I/O	I/O
AC12	I/O	QCLKA
AC13	I/O	I/O
AC14	I/O	I/O
AC15	I/O	I/O
AC16	I/O	I/O
AC17	I/O	I/O
AC18	I/O	I/O
AC19	I/O	I/O
AC20	V _{CCI}	V _{CCI}
AC21	I/O	I/O
AC22	I/O	I/O
AC23	NC*	I/O
AC24	I/O	I/O
AC25	NC*	I/O
AC26	NC*	I/O
AD1	I/O	I/O
AD2	I/O	I/O
AD3	GND	GND
AD4	I/O	I/O
AD5	I/O	I/O
AD6	I/O	I/O
AD7	I/O	I/O
AD8	I/O	I/O
AD9	V _{CCI}	V _{CCI}
AD10	I/O	I/O
AD11	I/O	I/O
AD12	I/O	I/O
AD13	V _{CCI}	V _{CCI}
AD14	I/O	I/O
AD15	I/O	I/O
AD16	I/O	I/O
AD17	V _{CCI}	V _{CCI}

Note: *These pins must be left floating on the A54SX32A device.